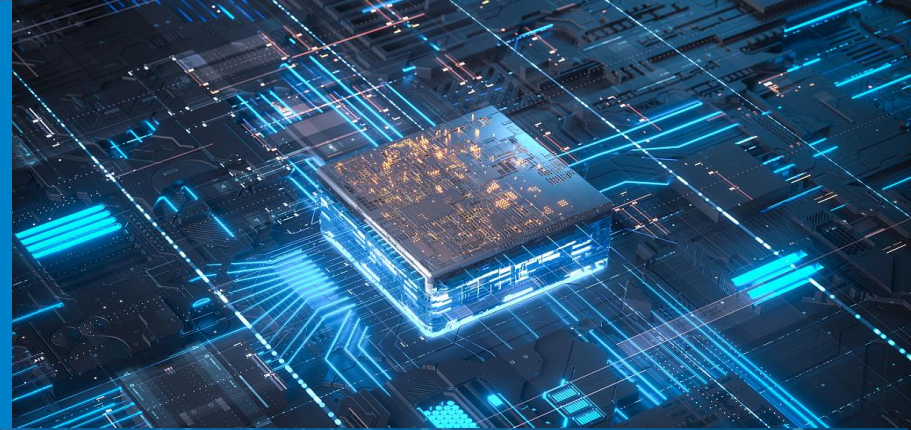


DATE 05/24/2023

ROLE OF HETEROGENEOUS INTEGRATION FOR ENERGY EFFICIENCY



MOINUDDIN AHMED, Ph.D.
Technical Lead
Electronic Materials Characterization Group
Applied Materials Division

FUTURE OF COMPUTING

More Moore

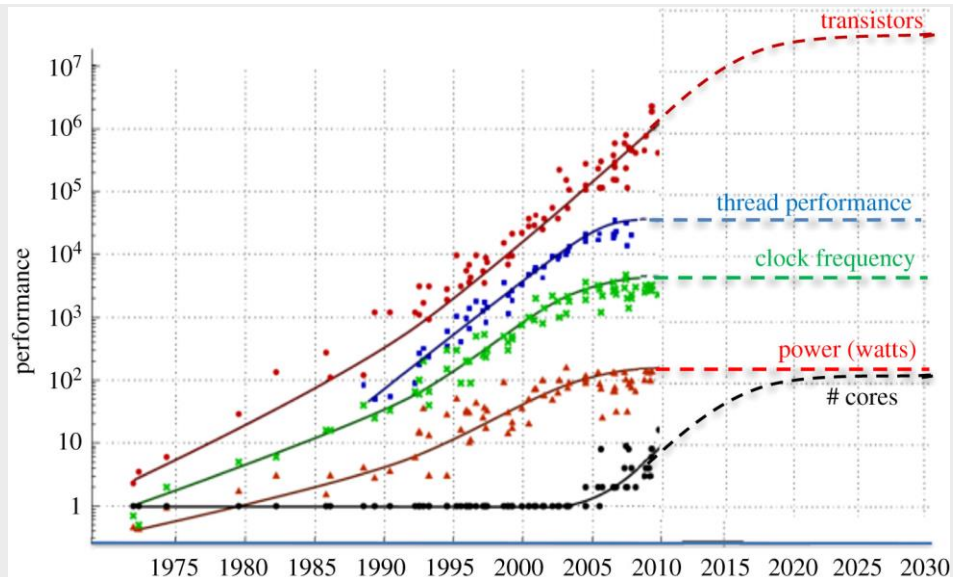
Challenges:

- End of Dennard Scaling

Scaling transistors down improves speed and reduces energy consumption

- Heat removal issues- clock-based scaling

- Focus: more power efficient and less expensive to build

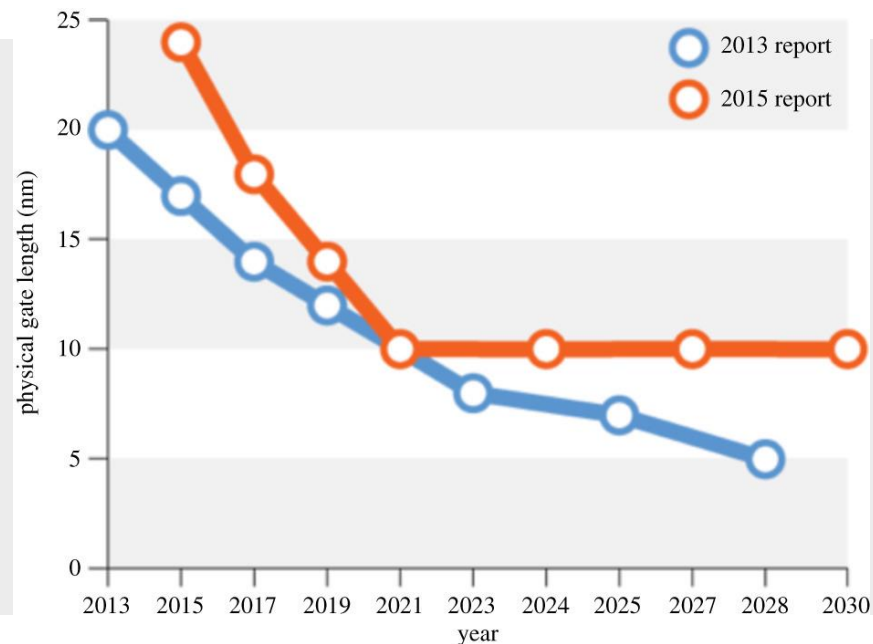


<https://doi.org/10.1098/rsta.2019.0061>

FUTURE OF COMPUTING

More Moore

- End of lithographic scaling
- ITRS report predicts transistor scaling will end in 2021

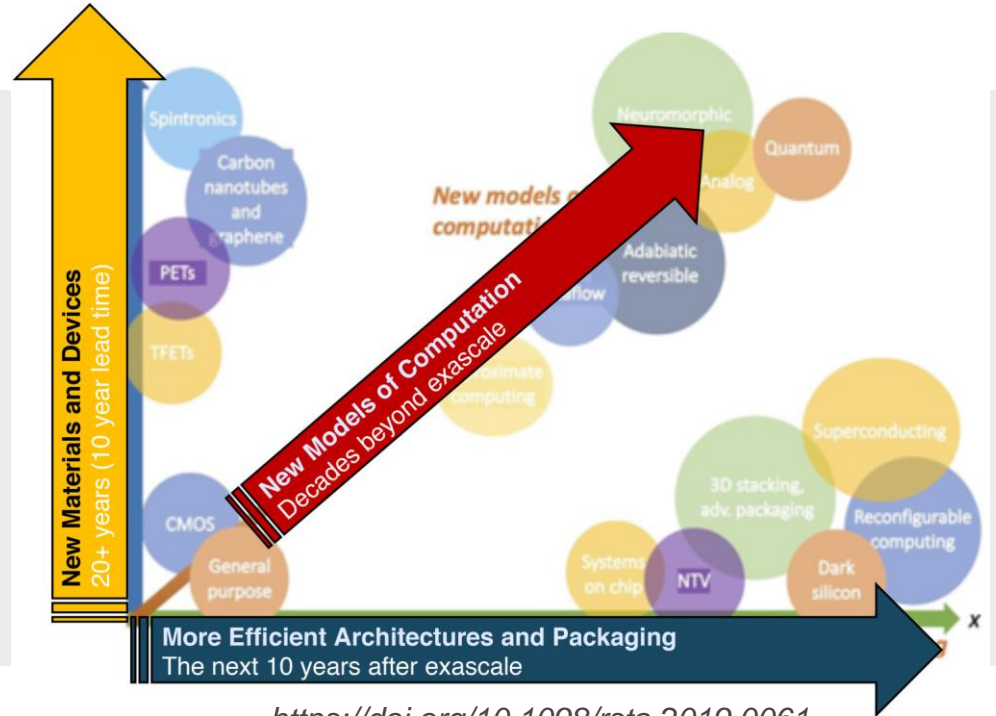


<https://doi.org/10.1098/rsta.2019.0061>

FUTURE OF COMPUTING

More than Moore

- Integrating functionalities at system level
 - More functions lower system cost*
- Adding analog, RF, MEMS, HV circuitry, control and passive components

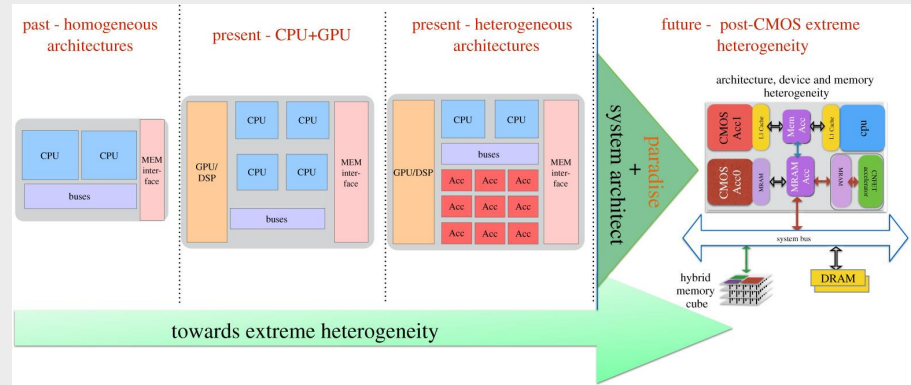


<https://doi.org/10.1098/rsta.2019.0061>

HETEROGENEOUS INTEGRATION

More than Moore and Beyond's Moore

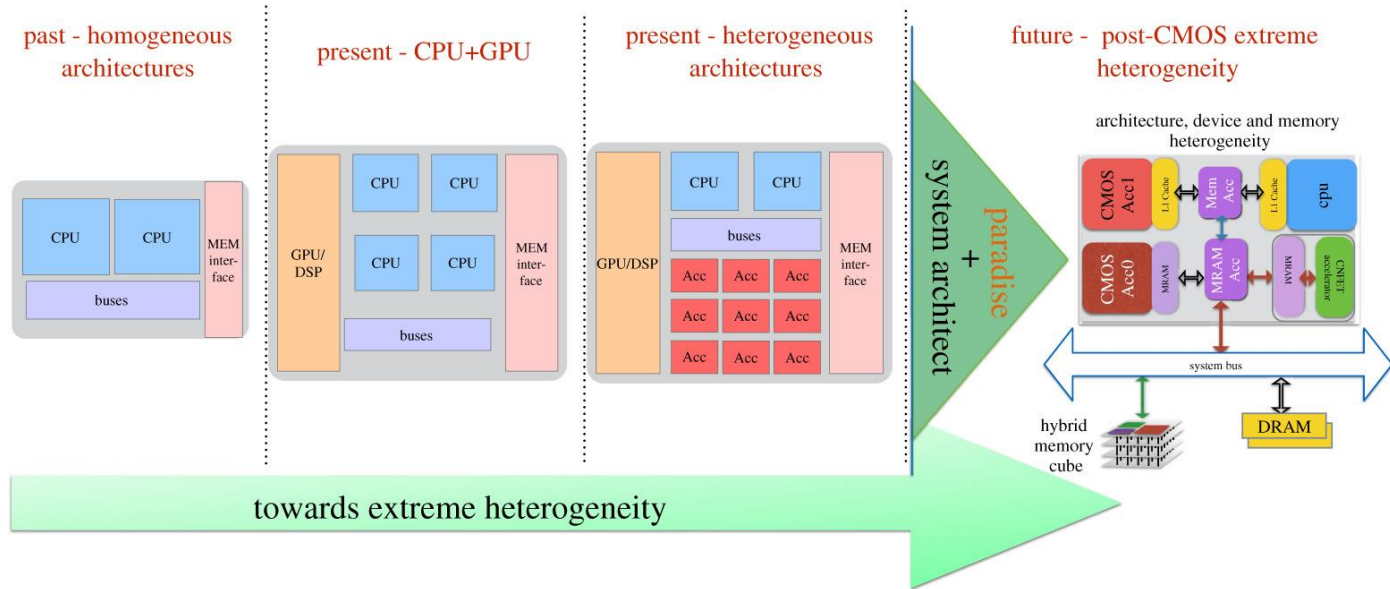
- Near-term response: architectural specialization and extreme heterogeneity
- Provide additional value to end application



<https://doi.org/10.1098/rsta.2019.0061>

HETEROGENEOUS INTEGRATION

More than Moore and Beyond's Moore

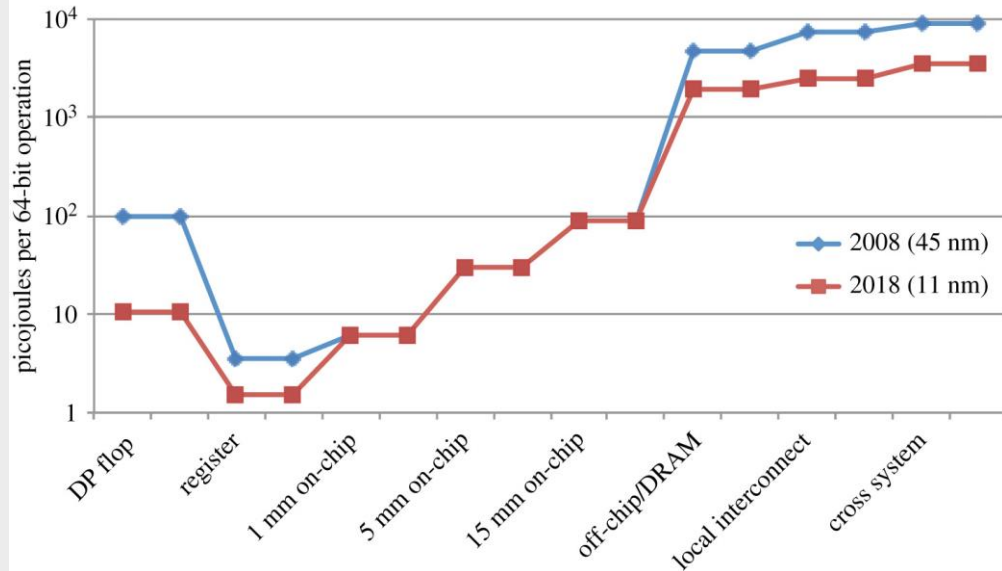


HETEROGENEOUS INTEGRATION

Beyond's Moore- Challenges ahead

- Energy efficiency of transistors is improving as sizes shrink
- Energy efficiency of wires is not improving

We have come to a point where the energy needed to move data exceeds the energy used to perform the operation on those data



<https://doi.org/10.1098/rsta.2019.0061>

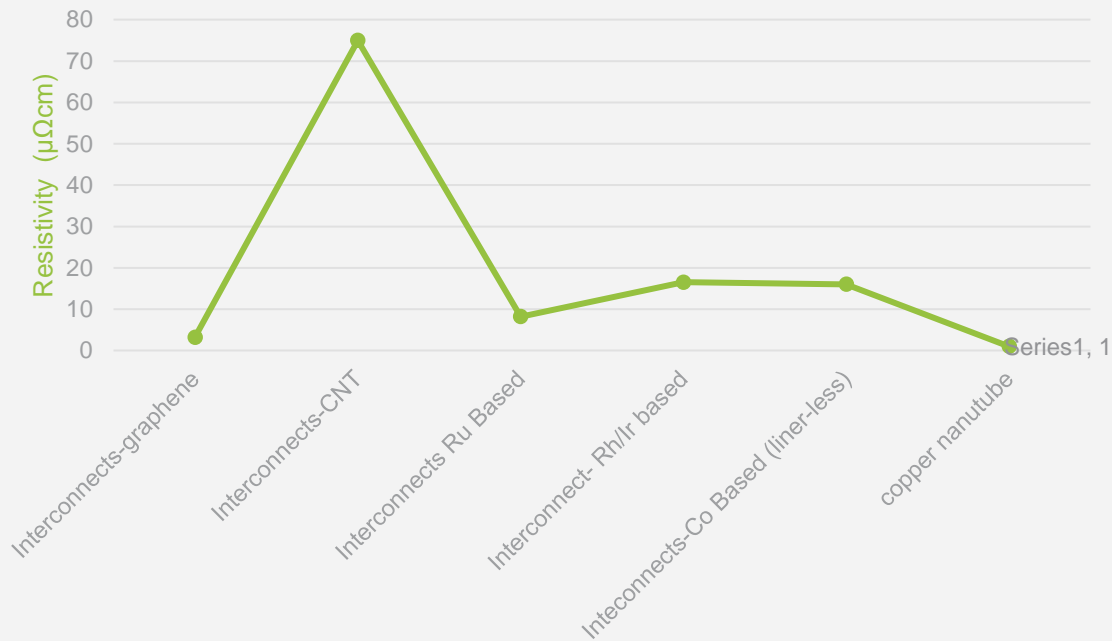
HETEROGENEOUS INTEGRATION

What's next?

- Advancing interconnect
- Advancing packaging, thermal interface etc

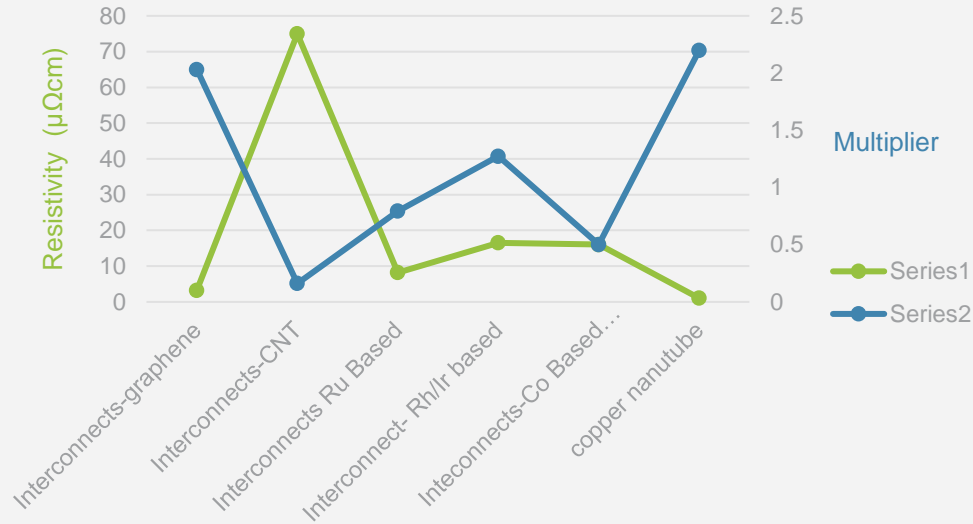
HETEROGENEOUS INTEGRATION

Advancing interconnect –replacing Cu



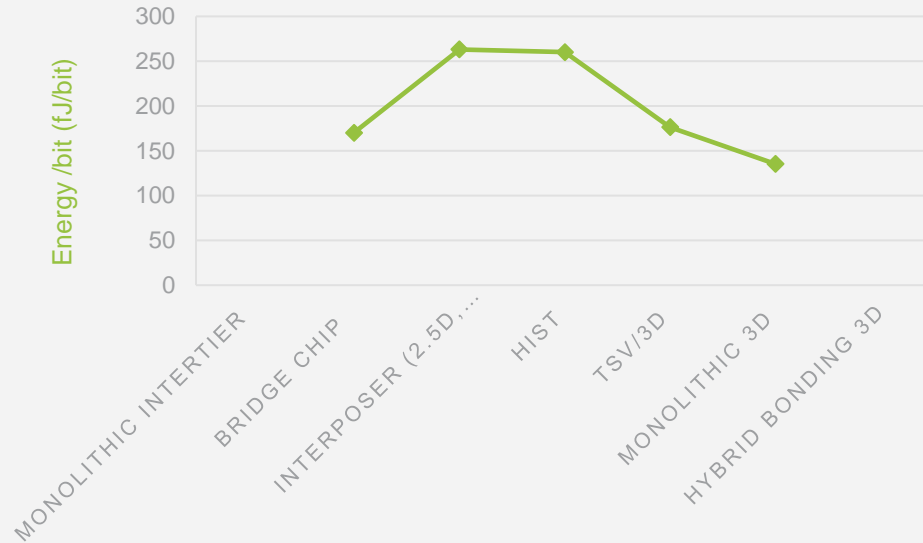
HETEROGENEOUS INTEGRATION

Advancing interconnect –replacing Cu



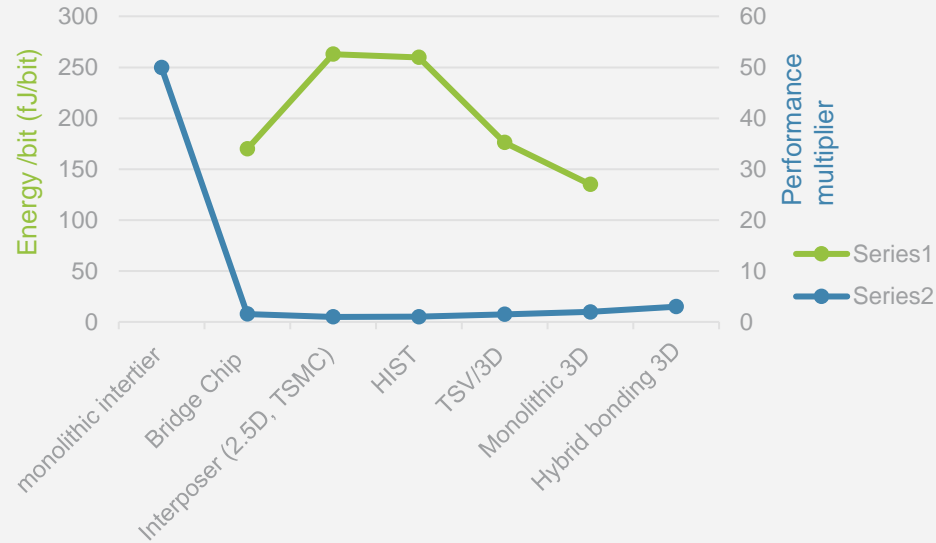
HETEROGENEOUS INTEGRATION

Interconnects-for enabling chip stacking



HETEROGENEOUS INTEGRATION

Interconnects-for enabling chip stacking



THANK YOU

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